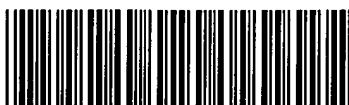


Search Notes

Application/Control No.

10/645,244

Examiner

Shih-Chao Chen

Applicant(s)/Patent under
Reexamination

MEIER ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
343	700MS, 702, 757, 848, 853, 893	3/3/2005	CHEN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
343	700MS	3/7/2005	CHEN
343	757, 853	3/7/2005	CHEN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (See attached printout).	3/3/2005	CHEN